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1	BRS	L1	18	(fail adj bit with (compress\$3 or encod\$3 or cod\$3))	USPAT	2004/05/13 22:03
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3	BRS	L3	3	2 and (fail with (shape or bound\$5 or contour))	USPAT	2004/05/13 22:05
4	BRS	L4	0	2 and (fail with (shape or bound\$5 or contour) same (ratio or rate))	USPAT	2004/05/13 22:06
5	BRS	L5	79	(fail or defect\$5) adj bit with (compress\$3 or encod\$3 or cod\$3)	USPAT	2004/05/13 22:06
6	BRS	L6	28	5 and ((fail or defect\$5) with (area or map))	USPAT	2004/05/13 22:07
7	BRS	L7	4	6 and ((fail or defect\$5) with (shape or bound\$5 or contour))	USPAT	2004/05/13 22:07
8	BRS	L8	0	7 and ((fail or defect\$5) with (shape or bound\$5 or contour) same (ratio or rate))	USPAT	2004/05/13 22:06
9	BRS	L9	47	(fail or defect\$5) adj bit with (compress\$3 or encod\$3 or cod\$3)	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:06
10	BRS	L10	13	9 and ((fail or defect\$5) with (area or map))	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:07
11	BRS	L11	1	10 and ((fail or defect\$5) with (shape or bound\$5 or contour))	US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:08

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Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 29-31 Jan. 2002

Pages:142 - 145

[\[Abstract\]](#) [\[PDF Full-Text \(278 KB\)\]](#) **IEEE CNF**
**17 Pseudo fail bit map generation for RAMs during component test and burn-in in a manufacturing environment***Vollrath, J.; Rooney, R.;*

Test Conference, 2001. Proceedings. International , 30 Oct.-1 Nov. 2001

Pages:768 - 775

[\[Abstract\]](#) [\[PDF Full-Text \(607 KB\)\]](#) **IEEE CNF**
**18 DC coefficient restoration using MAP estimation technique***Fu-Wing Tse; Wai-Kuen Cham;*

Acoustics, Speech, and Signal Processing, 1998. ICASSP '98. Proceedings of the 1998 IEEE International Conference on , Volume: 5 , 12-15 May 1998

Pages:2557 - 2560 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(464 KB\)\]](#) **IEEE CNF**
**19 Data compression in the V.42bis modems***Lettieri, A.; Holtz, K.; Holtz, E.;*

WESCON/94. 'Idea/Microelectronics'. Conference Record , 27-29 Sept. 1994

Pages:398 - 403

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) **IEEE CNF**

---

**20 A defect-tolerant design for mask ROMs***Iwasaki, K.; Fujiwara, T.; Kasami, T.;*

VLSI Test Symposium, 1992. '10th Anniversary. Design, Test and Application ASICs and Systems-on-a-Chip', Digest of Papers., 1992 IEEE , 7-9 April 1992  
Pages:171 - 175

[\[Abstract\]](#) [\[PDF Full-Text \(296 KB\)\]](#) [IEEE CNF](#)

---

**21 A wafer scale fail bit analysis system for VLSI memory yield improvement***Sakai, Y.; Sawada, J.; Sakamoto, W.; Murato, J.; Kawamoto, H.; Sakai, K.; Nakamuta, K.;*

Microelectronic Test Structures, 1990. ICMTS 1990. Proceedings of the 1990 International Conference on , 5-7 March 1990  
Pages:175 - 178

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